

Notice of References Cited	Application/Control No. 10/604,818	Applicant(s)/Patent Under Reexamination CHANG, YI-CHEN	
	Examiner Michael Pervan	Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,924,602	08-2005	Komiya, Naoaki	315/169.3
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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